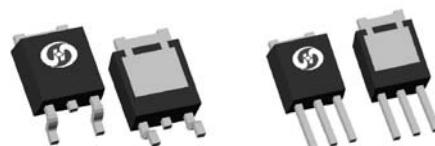


**250V N-Ch Power MOSFET**

$V_{DS}$	250	V
$R_{DS(on),typ}$	$V_{GS}=10V$	180 mΩ
$R_{DS(on),typ}$	$V_{GS}=4.5V$	190 mΩ
$I_D$ (Silicon Limited)	8.82	A



Part Number	Package	Marking
HGD2K4N25ML	TO-252	GD2K4N25ML
HGI2K4N25ML	TO-251	GI2K4N25ML Pin2

**Absolute Maximum Ratings at  $T_J=25^\circ C$  (unless otherwise specified)**

Parameter	Symbol	Conditions	Value	Unit
Continuous Drain Current (Silicon Limited)	$I_D$	$T_C=25^\circ C$	12.5	A
		$T_C=100^\circ C$	8.8	
Drain to Source Voltage	$V_{DS}$	-	250	V
Gate to Source Voltage	$V_{GS}$	-	$\pm 20$	V
Pulsed Drain Current	$I_{DM}$	-	18	A
Avalanche Energy, Single Pulse	$E_{AS}$	$L=0.4mH, T_C=25^\circ C$	1.8	mJ
Power Dissipation	$P_D$	$T_C=25^\circ C$	83	W
Operating and Storage Temperature	$T_J, T_{stg}$	-	-55 to 175	

**Absolute Maximum Ratings**

Parameter	Symbol	Max	Unit
Thermal Resistance Junction-Case	$R_{JC}$	1.8	°C/W
Thermal Resistance Junction-Ambient	$R_{JA}$	65	°C/W

**Electrical Characteristics at  $T_j=25^\circ\text{C}$  (unless otherwise specified)**
**Static Characteristics**

Parameter	Symbol	Conditions	Value			Unit
			min	typ	max	
Drain to Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{\text{GS}}=0\text{V}, I_D=250\mu\text{A}$	250	-	-	V
Gate Threshold Voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{GS}}=V_{\text{DS}}, I_D=250\mu\text{A}$	1	2.1	3	
Zero Gate Voltage Drain Current	$I_{\text{DSS}}$	$V_{\text{GS}}=0\text{V}, V_{\text{DS}}=250\text{V}, T_j=25^\circ\text{C}$	-	-	1	$\mu\text{A}$
		$V_{\text{GS}}=0\text{V}, V_{\text{DS}}=250\text{V}, T_j=100^\circ\text{C}$	-	-	100	
Gate to Source Leakage Current	$I_{\text{GSS}}$	$V_{\text{GS}}=\pm20\text{V}, V_{\text{DS}}=0\text{V}$	-	-	$\pm100$	nA
Drain to Source on Resistance	$R_{\text{DS}(\text{on})}$	$V_{\text{GS}}=10\text{V}, I_D=3\text{A}$	-	180	240	$\text{m}\Omega$
	$R_{\text{DS}(\text{on})}$	$V_{\text{GS}}=4.5\text{V}, I_D=2\text{A}$	-	190	280	$\text{m}\Omega$
Transconductance	$g_{\text{fs}}$	$V_{\text{DS}}=5\text{V}, I_D=20\text{A}$	-	11	-	S
Gate Resistance	$R_G$	$V_{\text{GS}}=0\text{V}, V_{\text{DS}} \text{ Open}, f=1\text{MHz}$	-	5.3	-	$\Omega$

**Dynamic Characteristics**

Input Capacitance	$C_{\text{iss}}$	$V_{\text{GS}}=0\text{V}, V_{\text{DS}}=125\text{V}, f=1\text{MHz}$	-	490	-	pF
Output Capacitance	$C_{\text{oss}}$		-	12	-	
Reverse Transfer Capacitance	$C_{\text{rss}}$		-	4.2	-	
Total Gate Charge	$Q_g (10\text{V})$	$V_{\text{DD}}=125\text{V}, I_D=3\text{A}, V_{\text{GS}}=10\text{V}$	-	10	-	nC
Total Gate Charge	$Q_g (4.5\text{V})$		-	6	-	
Gate to Source Charge	$Q_{\text{gs}}$		-	1.6	-	
Gate to Drain (Miller) Charge	$Q_{\text{gd}}$		-	3.6	-	
Turn on Delay Time	$t_{\text{d(on)}}$	$V_{\text{DD}}=125\text{V}, I_D=3\text{A}, V_{\text{GS}}=10\text{V}, R_G=10\Omega$	-	10	-	ns
Rise time	$t_r$		-	6	-	
Turn off Delay Time	$t_{\text{d(off)}}$		-	15	-	
Fall Time	$t_f$		-	5	-	

**Reverse Diode Characteristics**

Diode Forward Voltage	$V_{\text{SD}}$	$V_{\text{GS}}=0\text{V}, I_F=20\text{A}$	-	0.9	1.2	V
Reverse Recovery Time	$t_{\text{rr}}$	$V_R=125\text{V}, I_F=3\text{A}, dI_F/dt=100\text{A}/\mu\text{s}$	-	40	-	ns
Reverse Recovery Charge	$Q_{\text{rr}}$		-	82	-	nC

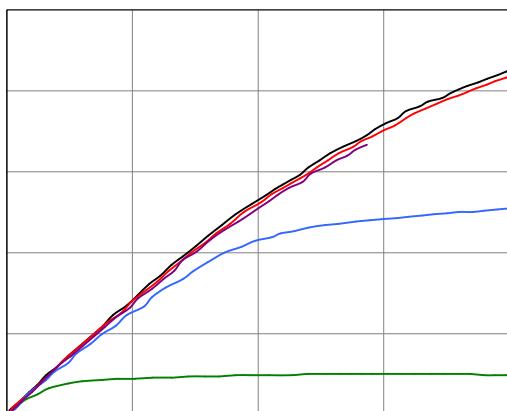
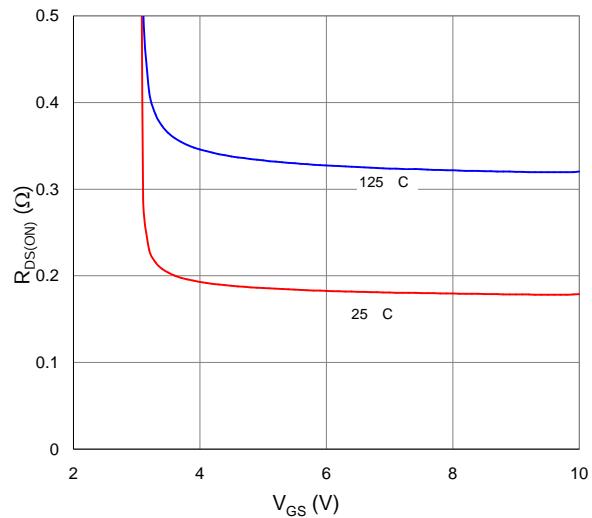
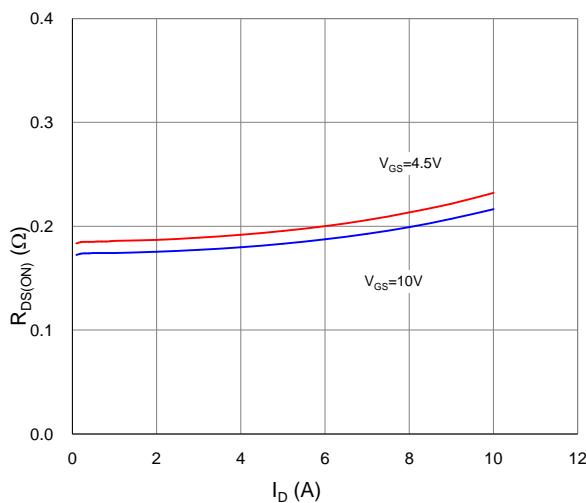
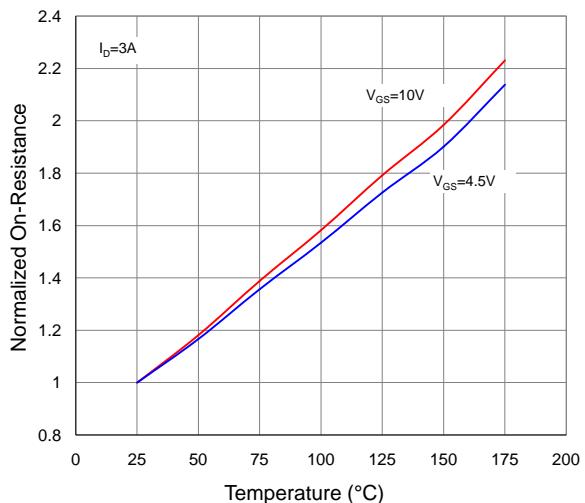
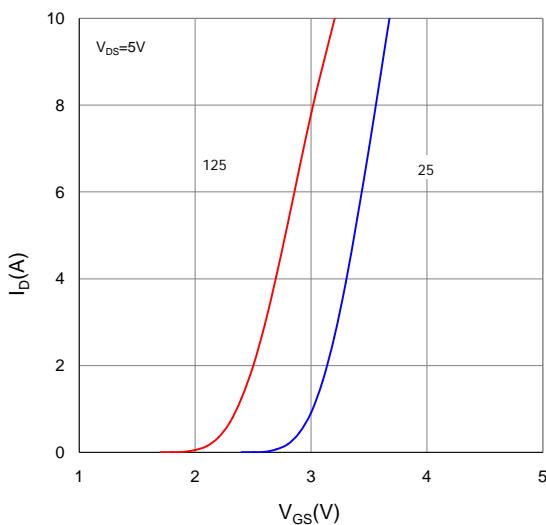
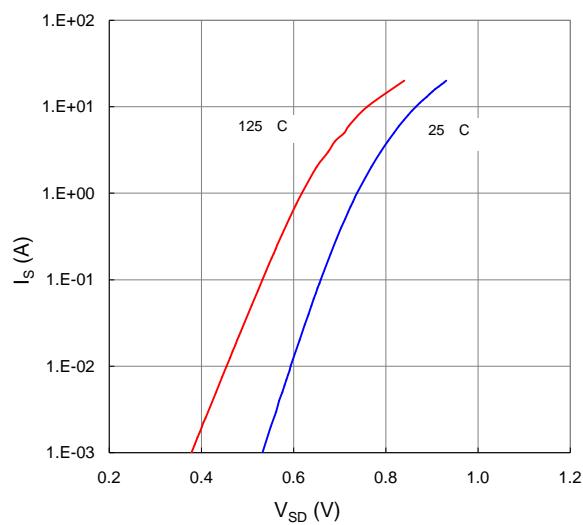
**Fig 1. Typical Output Characteristics**

**Figure 2. On-Resistance vs. Gate-Source Voltage**

**Figure 3. On-Resistance vs. Drain Current and Gate Voltage**

**Figure 4. Normalized On-Resistance vs. Junction Temperature**

**Figure 5. Typical Transfer Characteristics**

**Figure 6. Typical Source-Drain Diode Forward Voltage**


Figure 7. Typical Gate-Charge vs. Gate-to-Source Voltage

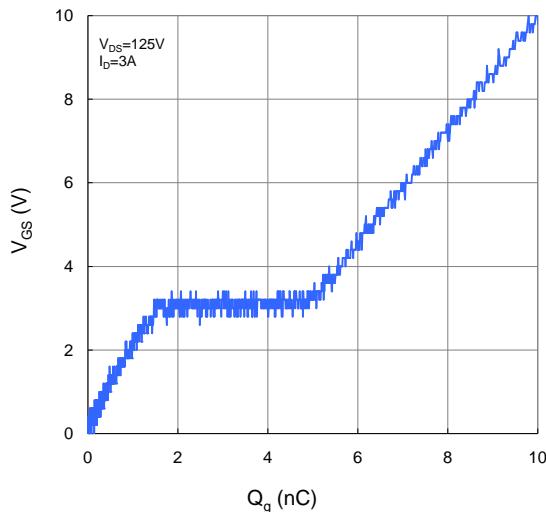


Figure 8. Typical Capacitance vs. Drain-to-Source Voltage

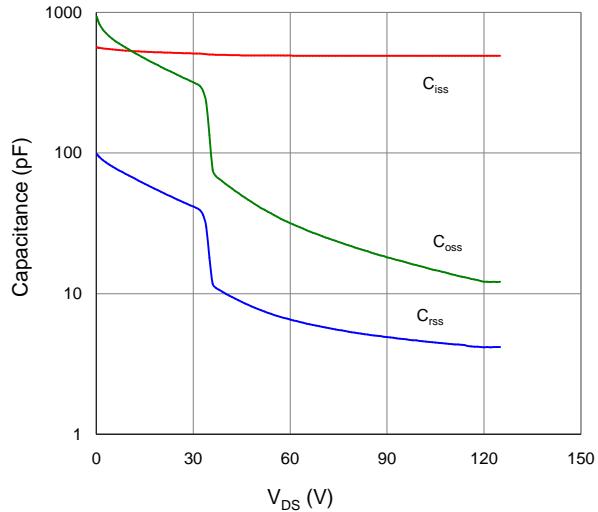


Figure 9. Maximum Safe Operating Area



Figure 10. Maximum Drain Current vs. Case Temperature

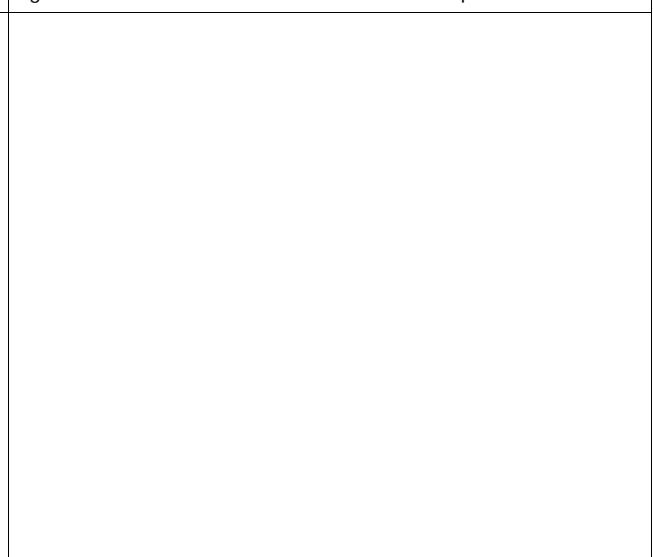
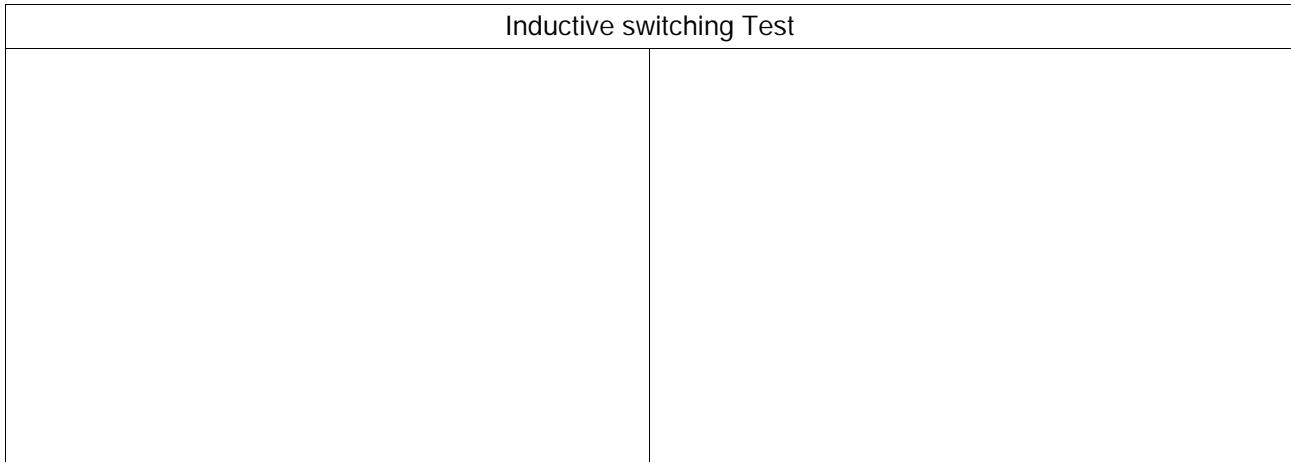
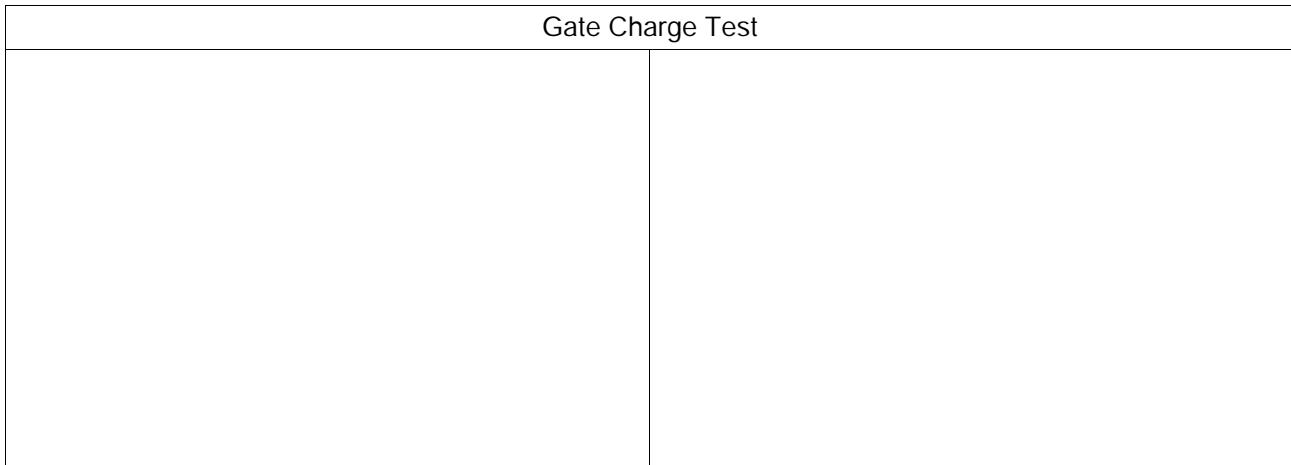


Figure 11. Normalized Maximum Transient Thermal Impedance, Junction-to-Case

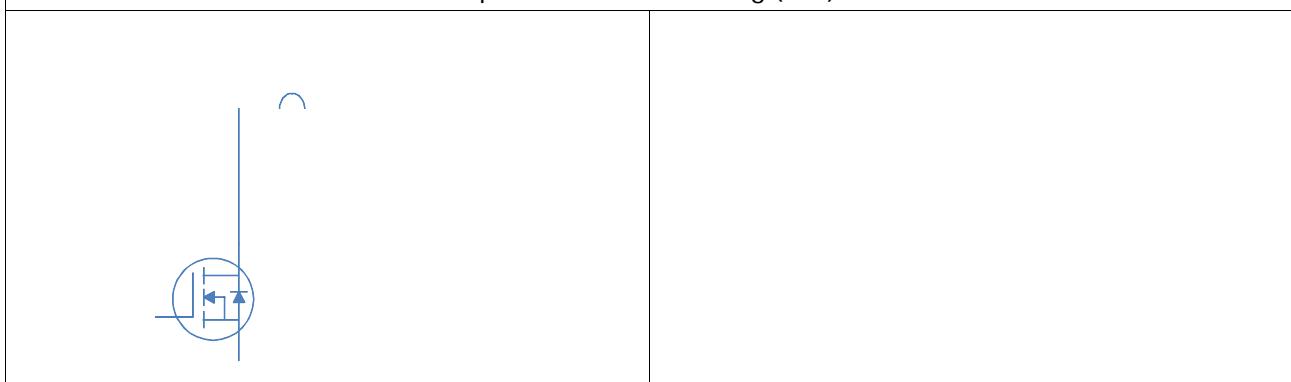
## Inductive switching Test



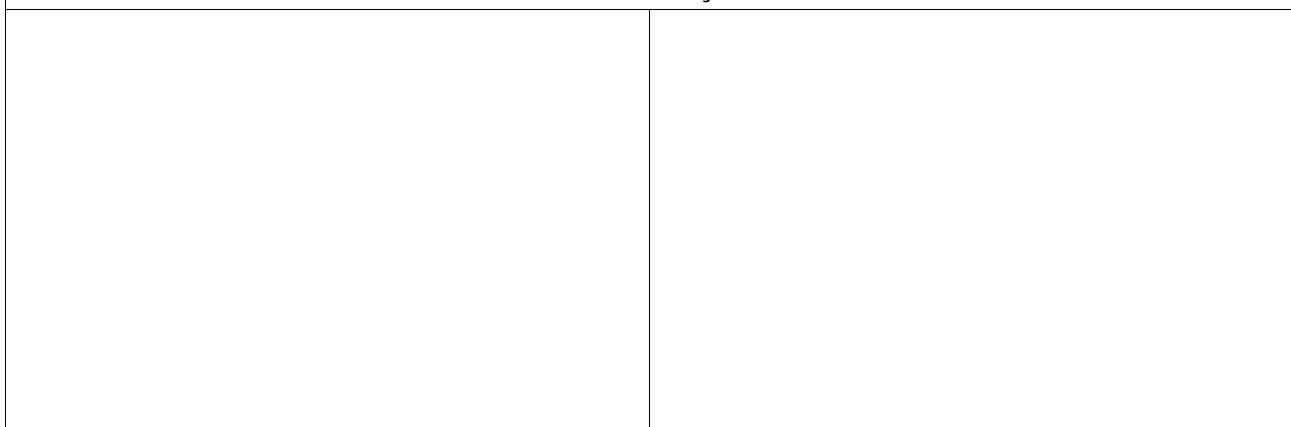
## Gate Charge Test

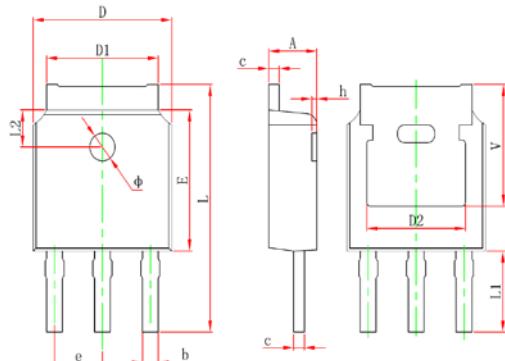


## Uclamped Inductive Switching (UIS) Test

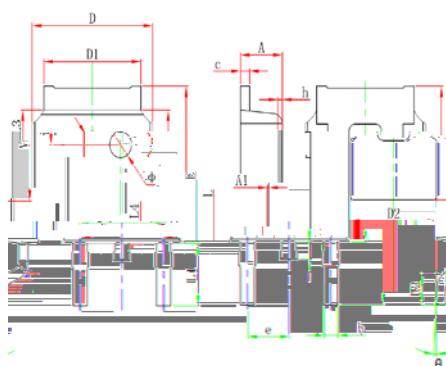


## Diode Recovery Test



**TO-251, 3 leads**


Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	2.200	2.400	0.087	0.094
D	6.500	6.700	0.260	0.266
c	0.460	0.580	0.018	0.026
D1	0.660	0.860	0.026	0.034
E	0.000	0.127	0.000	0.005
L	0.000	0.127	0.000	0.005
v	0.000	0.127	0.000	0.005
b	0.000	0.127	0.000	0.005
e	0.000	0.127	0.000	0.005
φ	0.000	0.127	0.000	0.005

**TO-252, 2 leads**


Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	2.200	2.400	0.087	0.094
A1	0.000	0.127	0.000	0.005
b	0.660	0.860	0.026	0.034
c	0.460	0.580	0.018	0.023
D	6.500	6.700	0.260	0.266
D1	0.660	0.860	0.026	0.034
E	0.000	0.127	0.000	0.005
L	0.000	0.127	0.000	0.005
v	0.000	0.127	0.000	0.005
b	0.000	0.127	0.000	0.005
e	0.000	0.127	0.000	0.005
φ	0.000	0.127	0.000	0.005